Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	50	("4800301" "5268645" "5777932" "6092226" "5964894" "4822295" "4573008" "6049740" "4342959" "5418960" "5600788" "6181004" "4894744" "6114848" "4556840" "4808915" "5627842" "6175230" "5477548" "5615217" "5925144" "5381420" "5406199" "5412575" "5425036" "5426372" "5444716" "5481463" "5581463" "5602855" "5631911" "5745500" "5794007" "5841788" "6000051" "6029261" "6081916" "6127833" "4630270" "4782283" "4794599" "4864219" "4992849" "4992850" "5247249" "5396186" "5487074" "5617044" "5757811" "5787114").pn.	US-PGPUB; USPAT	OR	ON	2004/11/18 15:13

10603407\_CLS.txt Most Frequently Occurring Classifications of Patents Returned From A Search of 10603407 on November 18, 2004

-1

MPEP 2173.05(1) Original Classifications 714/727 324/158.1 10 705/400 324/537 714/726 714/738 Cross-Reference Classifications 6 714/734 4 324/73.1 system system 714/726 714/733 222/638 222/639 324/754 377/15 714/724 257/E25.023 12 324/158.1 324/763 361/684 361/783 377/16 714/30 714/720 10 5 714/731 7 Combined Classifications 10 714/727 7 714/734 6 714/726 11 5/136  $3\overline{2}4/158.1$ metho à 324/73.1 714/733 324/754 714/724 222/638 222/639 324/537 377/15 705/400 714/731 714/738 20 257/E25.023 324/755 324/763 5/13 71 361/684 361/783 377/16 714/30 714/719 714/720 5TA6 Tech. - international
page 1

Standard

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Page 1

INCLUDING TIMER

INCLUDING TIMER

(0 OR, 3 XR) 222: DISPENSING

Class 222/638

Class 222/638

222/639

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10603407_CLSTITLES.txt
           222/639
                           .For timing dispensing period
                      (2 OR, 1 XR)
                     324 :
                           ELECTRICITY: MEASURING AND TESTING
           class
           324/500
                           FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                               ELECTRIC COMPONENTS
                            .Of individual circuit component or element
           324/537
  3 377/15
                      (0 \text{ OR}, 3 \text{ XR})
           Class
                            ELECTRICAL PULSE COUNTERS, PULSE DIVIDERS, OR
                              SHIFT REGISTERS: CIRCUITS AND SYSTEMS
           377/1
                           APPLICATIONS
           377/15
                           .Counting based on number of times machine or
                               apparatus operates
                      (3 OR, 0 XR)
    705/400
                    705 : DATA PROCESSING: FINANCIAL, BUSINESS
           Class
                              PRACTICE, MANAGEMENT, OR COST/PRICE DETERMINATION
           705/400
                           FOR COST/PRICE
  3 714/731
                     (1 OR, 2 XR)
                    714:
                            ERROR DETECTION/CORRECTION AND FAULT
           Class
                             DETECTION/RECOVERY
                           PULSE OR DATA ERROR HANDLING .Digital logic testing
           714/699
           714/724
                           ...Scan path testing (e.g., level sensitive scan design (LSSD))
...Clock or synchronization
           714/726
           714/731
                    (2 OR, 1 XR)
714 : ERROR DETECTION/CORRECTION AND FAULT
  3 714/738
           Class
                             DETECTION/RECOVERY
                           PULSE OR DATA ERROR HANDLING .Digital logic testing
           714/699
           714/724
           714/738
                           ..Including test pattern generator
  2 257/E25.023
                    (0 OR, 2 XR)
           Class
                    257 : ACTIVE SOLID-STATE DEVICES
                           ASSEMBLIES CONSISTING OF PLURALITY OF
           257/E25.001
                                  INDIVIDUAL SEMICONDUCTOR OR OTHER SOLID-STATE DEVICES
(EPO)
                           .All devices being of same type, e.g., assemblies of rectifier diodes (EPO)
           257/E25.002
           257/E25.022
                           ..Devices having separate containers (EPO)
           257/E25.023
                           ... Device consisting of plurality of
                               semiconductor or other solid-state devices or components
                               formed in or on common substrate, e.g., integrated
circuit
                              device (EPO)
  2 324/755
                     (1 OR, 1 XR)
                    324 : ELECTRICITY: MEASURING AND TESTING
           Class
                           FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
.Of individual circuit component or element
           324/500
           324/537
           324/754
                           ..With probe elements
           324/755
                           ...Internal of or on support for device under
                              test (DUT)
                    (0 OR, 2 XR)
324 : ELECTRICITY: MEASURING AND TESTING
    324/763
           Class
           324/500
                           FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
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## 10603407\_CLSTITLES.txt **ELECTRIC COMPONENTS** .Of individual circuit component or element 324/537 324/763 ..DUT including test circuit 2 361/684 (0 OR, 2 XR) 361 : ELECTRICITY: ELECTRICAL SYSTEMS AND DEVICES Class 361/600 HOUSING OR MOUNTING ASSEMBLIES WITH DIVERSE **ELECTRICAL COMPONENTS** .For electronic systems and devices 361/679 ... Computer related support 361/683 361/684 ... Memory unit support 361/783 (0 OR, 2 XR)361 : ELECTRICITY: ELECTRICAL SYSTEMS AND DEVICES class 361/600 HOUSING OR MOUNTING ASSEMBLIES WITH DIVERSE **ELECTRICAL COMPONENTS** .For electronic systems and devices ..Printed circuit board ...Connection of components to board 361/679 361/748 361/760 361/783 .... Having semiconductive device (0 OR, 2 XR)2 377/16 Class 377 : ELECTRICAL PULSE COUNTERS, PULSE DIVIDERS, OR SHIFT REGISTERS: CIRCUITS AND SYSTEMS **APPLICATIONS** 377/16 .Determining machine or apparatus operating time or monitoring machine, apparatus or operation (0 OR, 2 XR) '14: ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY 2 714/30 class 714: 714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING .Reliability and availability 714/1 714/25 .. Fault locating (i.e., diagnosis or testing) 714/27 ...Particular access structure ....Built-in hardware for diagnosing or testing 714/30 within-system component (e.g., microprocessor test mode circuit, scan path) 2 714/719 (1 OR, 1 XR)ERROR DETECTION/CORRECTION AND FAULT 714: Class DETECTION/RECOVERY PULSE OR DATA ERROR HANDLING 714/699 .Memory testing ..Read-in with read-out and compare 714/718 714/719 714/720 (0 OR, 2 XR)ERROR DETECTION/CORRECTION AND FAULT class 714: DETECTION/RECOVERY 714/699 PULSE OR DATA ERROR HANDLING .Memory testing ..Read-in\_with read-out and compare 714/718

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walking ones)

... Special test pattern (e.g., checkerboard,

714/719 714/720

## 10603407\_QUAL.txt

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## 10603407\_LIST.txt

PLUS Search Results for S/N 10603407, Searched November 18, 2004

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